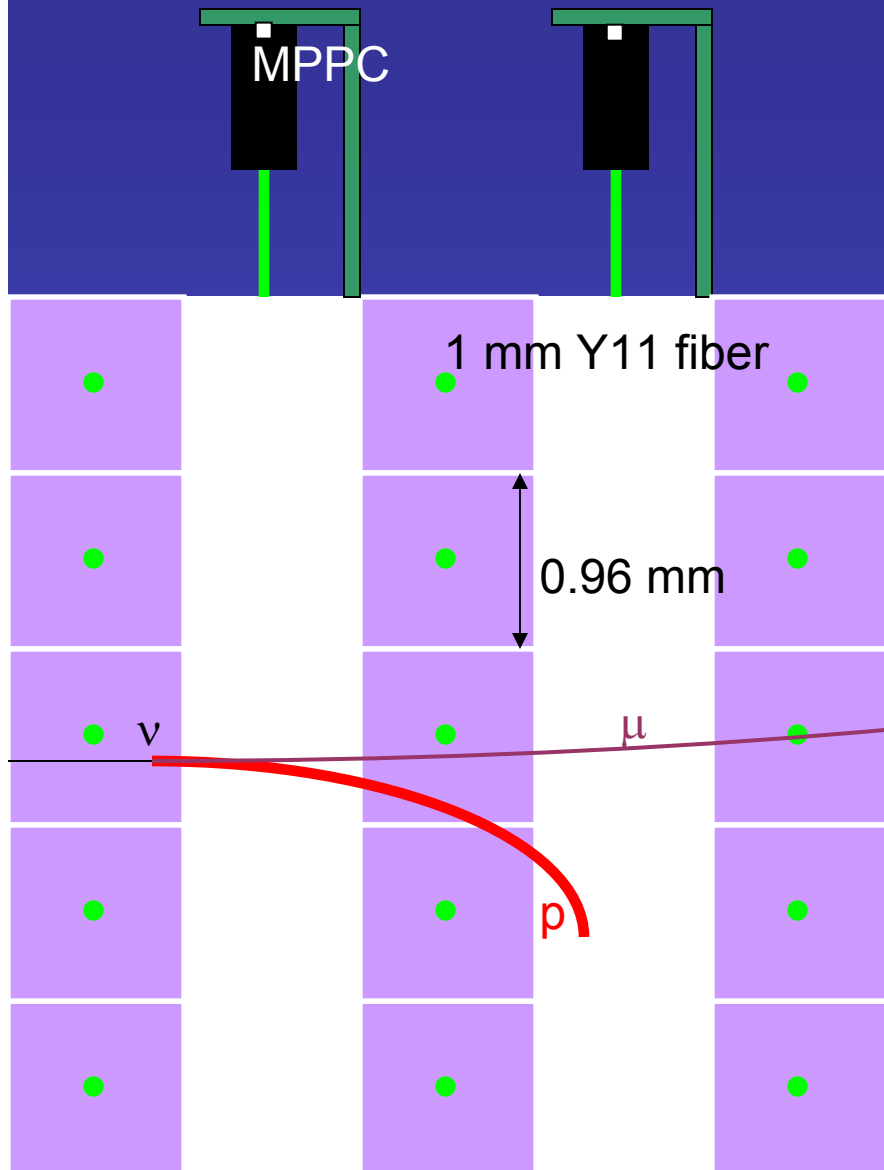


# Using MPPCs for T2K Fine Grain Detector

Fabrice Retière (TRIUMF)  
for the FGD group

University of British Columbia, Kyoto University,  
University of Regina, TRIUMF and University of Victoria

# T2K Fine Grain Detector



- ❑ Element of T2K near detector
- ❑ Active target for neutrino interaction
- ❑ Elements
  - Plastic scintillator bar (POPOP)
    - 2 meter long
  - Light collection with Wavelength Shifting fiber
  - Readout by Hamamatsu MPPC
  - ~10,000 channels

# FGD physics requirements

- ❑ 100% efficiency for MIP crossing a bar
- ❑ Particle identification
  - By  $dE/dx$  for particle crossing the FGD
  - By range, especially for stopping protons
    - Large energy released (10 MIPs)
  - By detecting Michel positrons for stopping  $\pi^+$
- ❑ Position resolution
  - Bar width & no information along the bar
- ❑ Timing resolution
  - $\sim 3\text{ns}$  per neutrino interaction for matching with photons in calorimeter

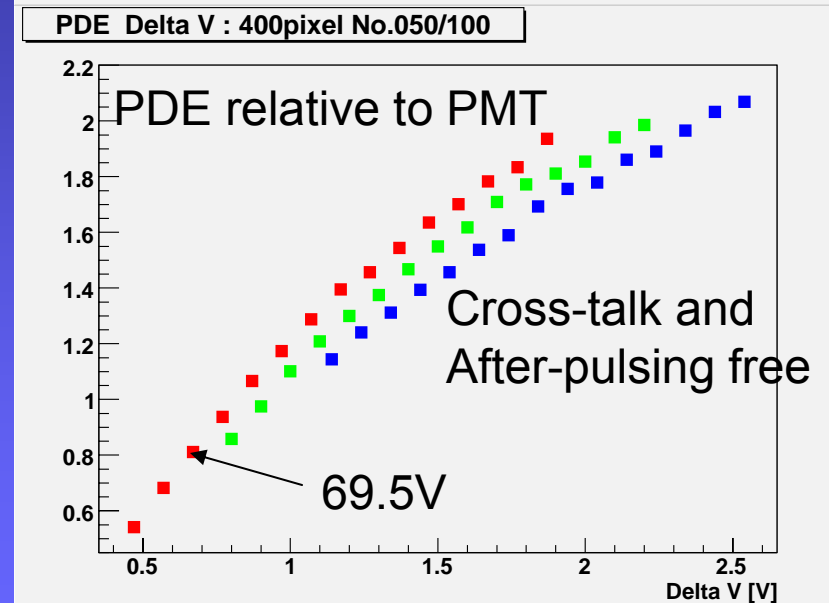
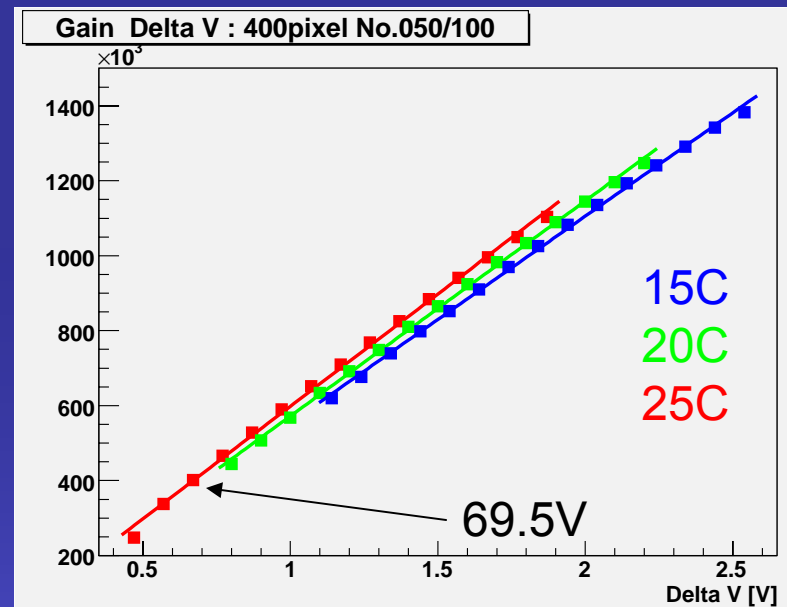
# MPPC basic parameters

□ Gain  $> 2 \cdot 10^5$

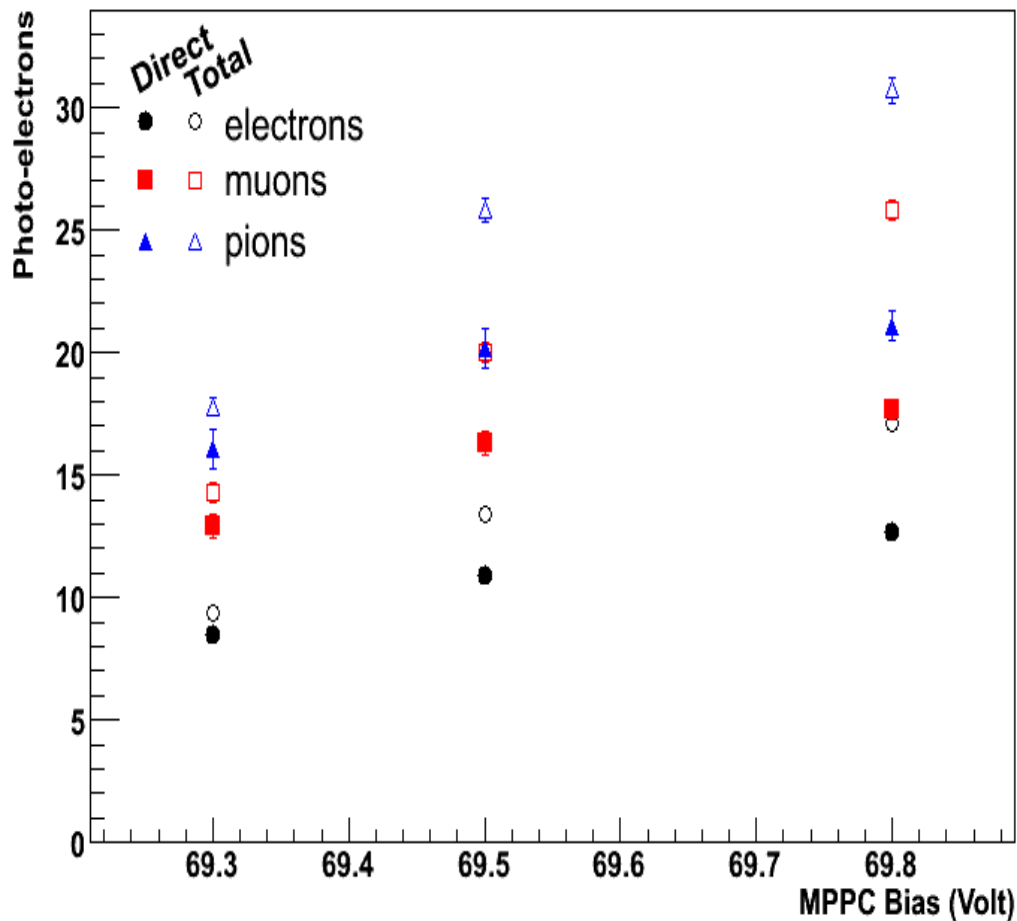
- i.e.  $1\text{PE} = 2 \cdot 10^5 e^-$ 
  - Way above typical electronics noise

□ Photo-detection efficiency

- Comparable or better than PMT
  - But need to measure PDE for proper wavelength



# Photo-electron per MIP MPPC fulfill requirements



- Beam test at TRIUMF
  - 120 MeV/c particles
- Electrons are minimum ionizing
- Worst case scenario
  - No fiber mirroring
  - End of the bar
- More than 10 direct PE even at 69.5V
  - No need to run at higher voltage
- Issue of Fiber-MPPC coupling still being addressed
  - New coupler
  - 1.2x1.2 mm<sup>2</sup> MPPC

# MPPC fulfilling requirements

## ❑ Quantum efficiency

- For 100% efficiency need more than 10 PE per MIP
  - Go for at least 15 PEs per MIP

## ❑ Energy resolution. Not directly a MPPC issue

- Driven by photon statistics (~25% for 15 PE)
  - Increase quantum efficiency would help

## ❑ Timing resolution.

- Not a MPPC issue in principle (fast)

## ❑ Dynamic range

- 400 pixels provide more than 50 MIPs dynamic range due to saturation

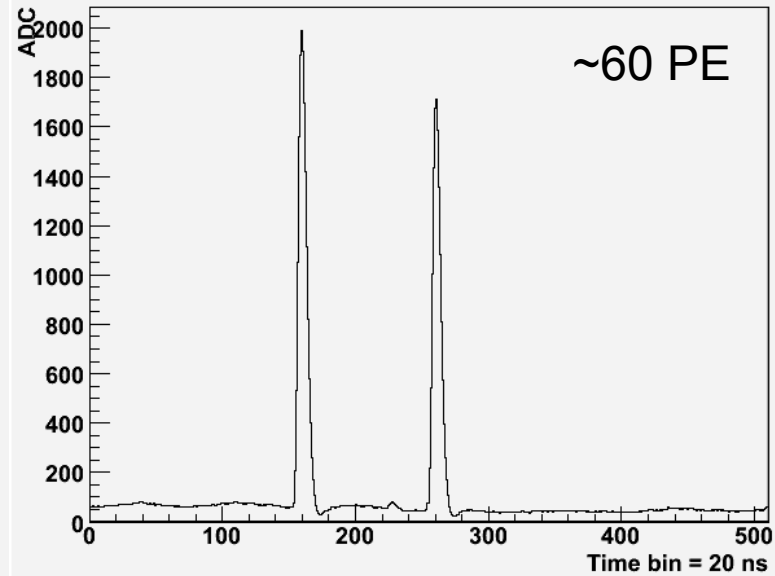
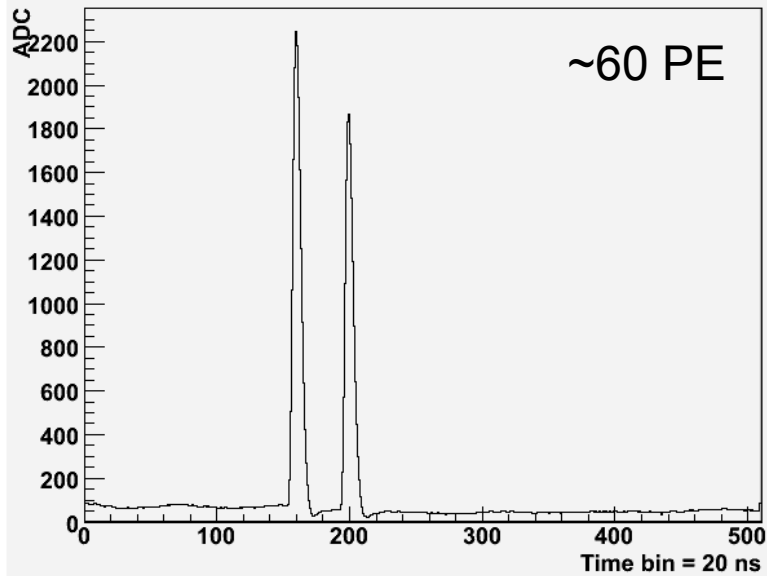
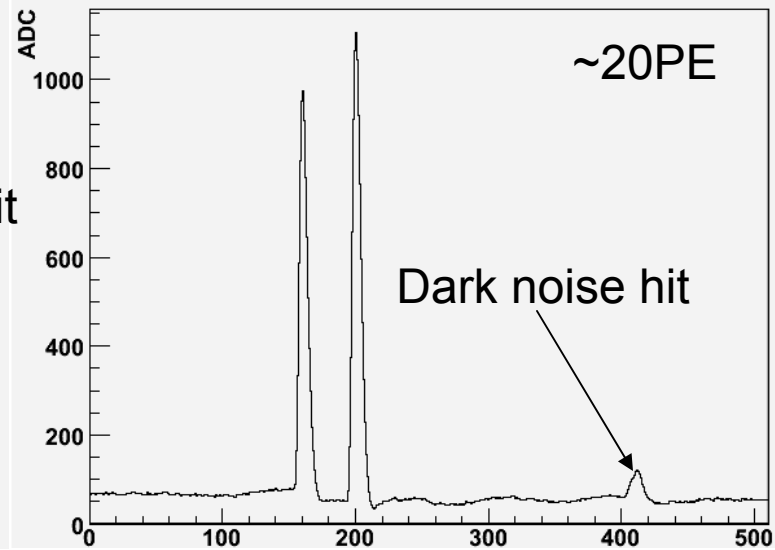
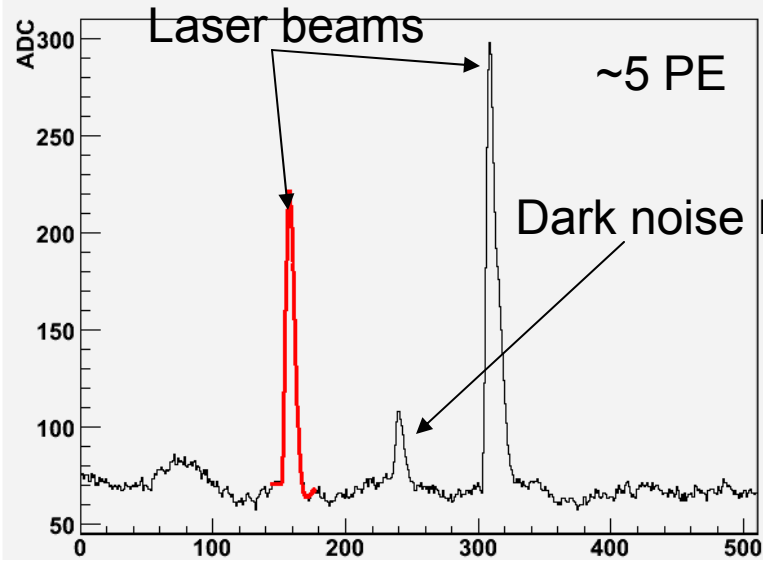
## ❑ Nuisances: Dark noise, cross-talk, after-pulsing

# Reading out MPPCs

## □ Compromise between timing resolution and integration time

- Desirable to measure all pulses continuously during beam spill ( $5 \mu\text{s}$ ) and about 2 muon decay constant ( $2.2 \mu\text{s}$ ) after spill
- Chose a waveform digitization solution
  - Use the Switch Capacitor Array designed for Time Projection Chamber (AFTER ASIC)
  - Fairly slow shaper (100 ns rise time)
  - 50 MHz sampling frequency
  - 512 time bin  $\sim 10 \mu\text{s}$  total integration time

# Waveforms from MPPC coupled to AFTER ASIC





# Fulfilling the dynamic range and energy resolution requirements

❑ For calibration need to identify 1 PE peak

- Noise set to 0.2 PE

❑ Maximum dynamic range = 400 PE

- After-pulsing may increase beyond 400 pixel

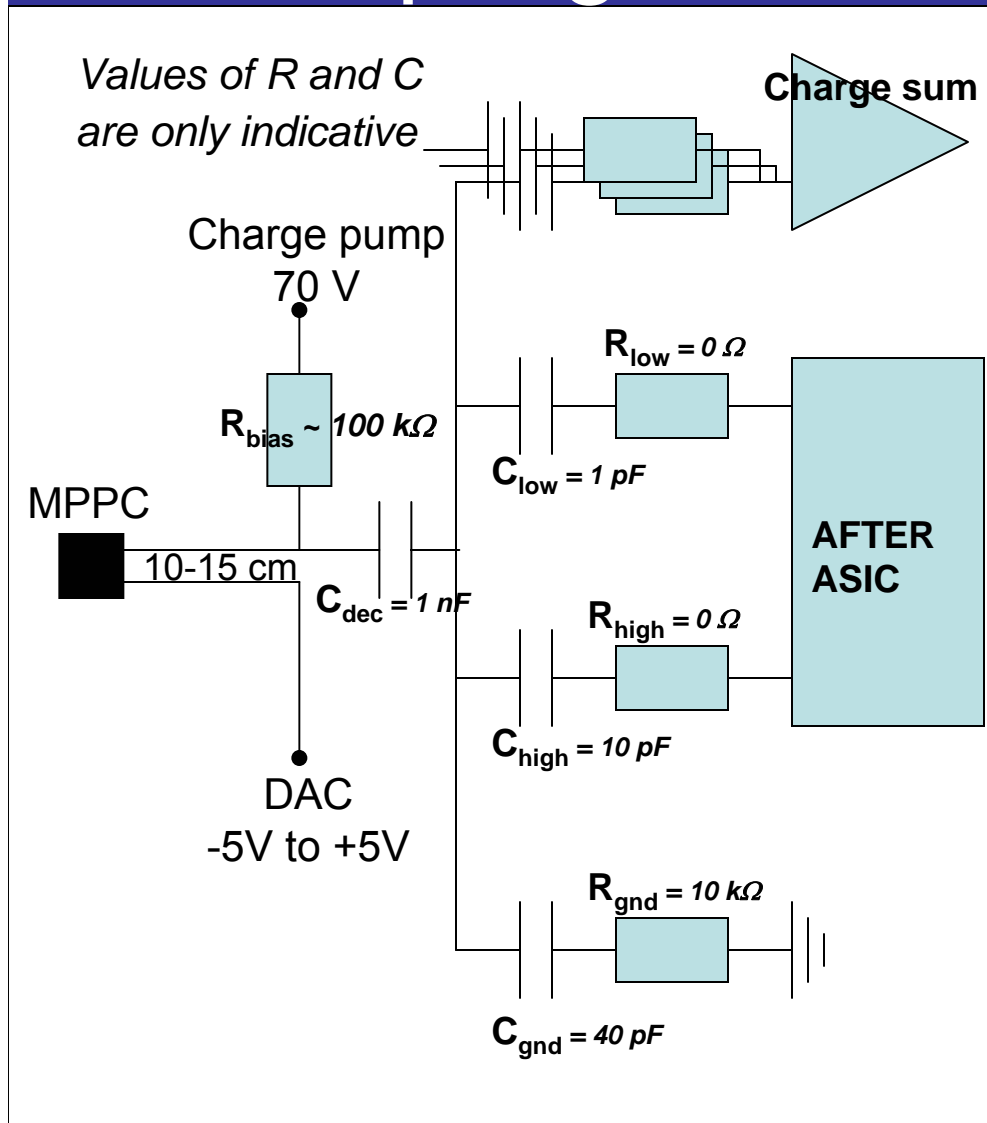
❑ ASIC noise  $\sim 2,000 e^-$

- MPPC gain  $\sim 5 \cdot 10^5$
- 0.2 PE noise  $\Rightarrow$  attenuate by  $\sim 50$

❑ ASIC dynamic range = 600 fC

- Dynamic range 0.2 PE to  $\sim 200$  PE
- Need another channel with higher attenuation

# Coupling AFTER ASIC to MPPC



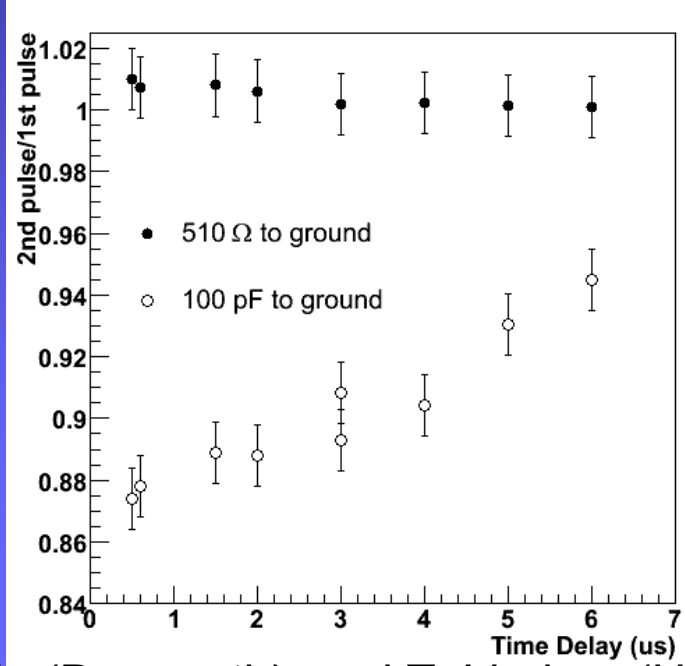
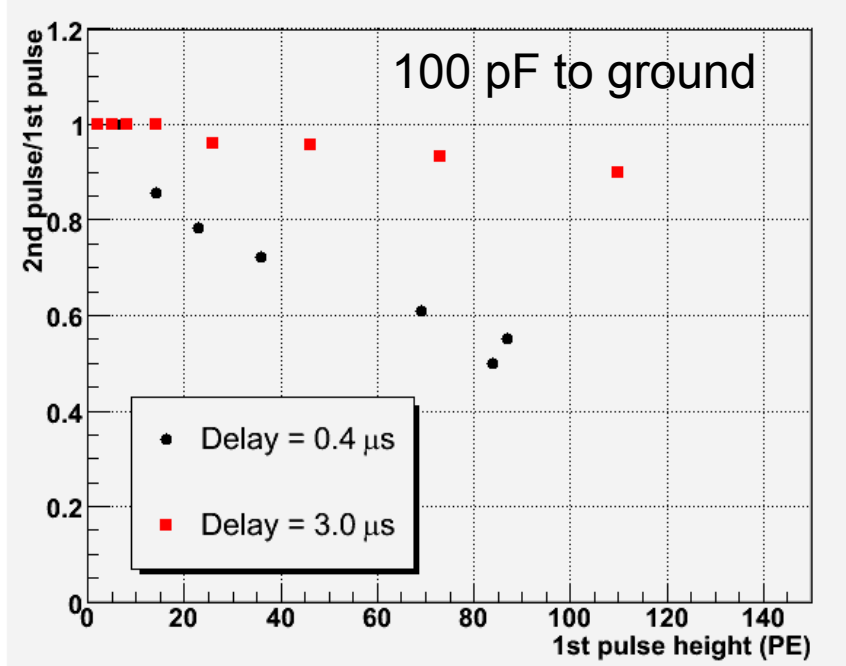
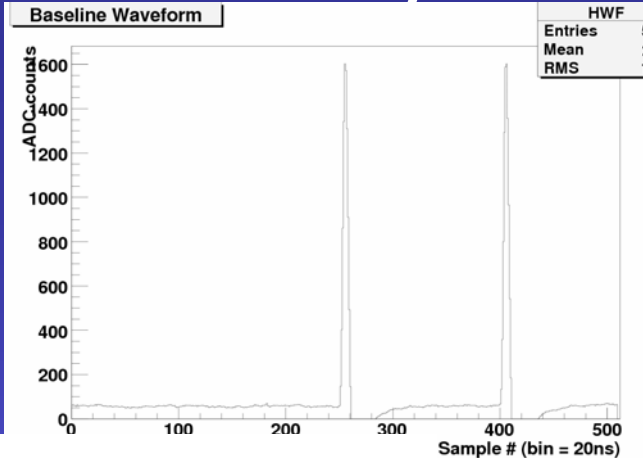
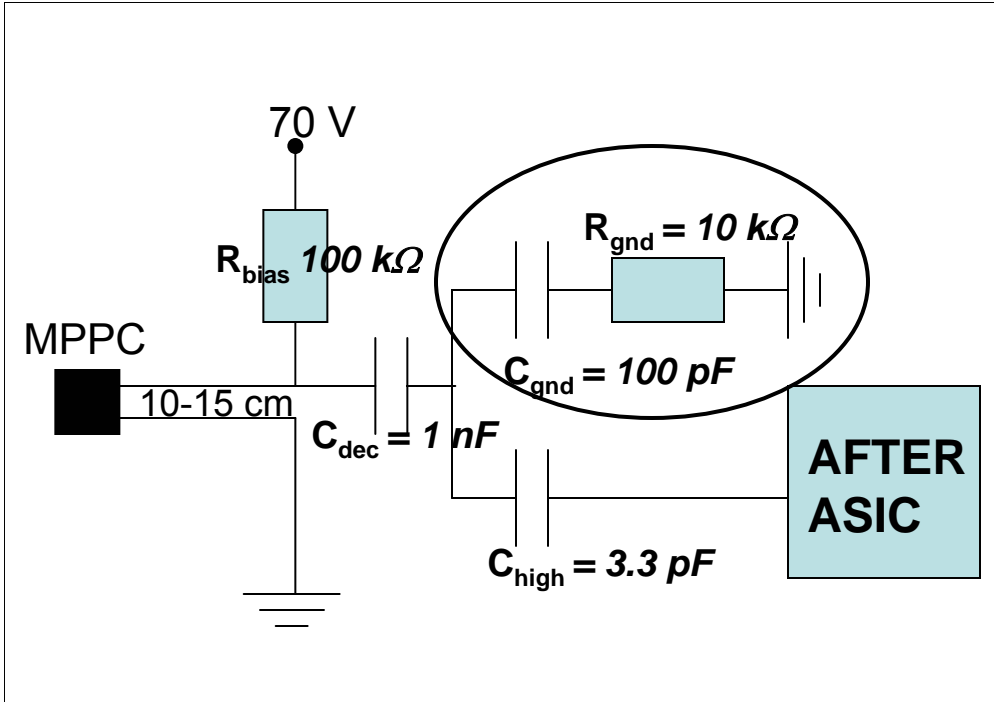
## Issues

- Attenuation
  - High/low input to ASIC
- Low input capacitance
  - Low electronic noise
- Noise from resistors
- MPPC recovery
  - Require small  $R_{bias}$  with purely capacitive termination
- Minimize reflections (50  $\Omega$  line)
- Pulse shape

## Solution

- Not clear yet. Some answer from Spice simulations
- Building a specific 8 channel prototype

# Pulse shape and recovery



N. Jain (Darmouth), and T. Lindner (UBC)

# Timing resolution

- ❑ Obtained by fitting waveforms
  - Fit rising edge only
- ❑ Source of fluctuations
  - Photon arrival time
    - Fiber and scintillator decay constants
- ❑ Waveform distortion
  - Dark noise
  - After-pulsing
    - Need to measure after-pulsing to evaluate effect

| Configuration              | Resolution for MIP (20 PE) |
|----------------------------|----------------------------|
| Simulations + waveform fit | 3 ns                       |
| Data + full waveform fit   | 5 ns                       |
| Data + rising edge fit     | 4±1 ns                     |

# Beyond the gross features

## Estimating the MPPC Nuisances

### □ Dark noise

- Add pulses. Increase data size
  - But useful for gain calibration
- At  $<500$  kHz, does not affect timing and energy resolution

### □ Cross-talk

- Marginal worsening of energy resolution (if  $<20\%$ )
- Increase number of PE
  - May skew timing resolution

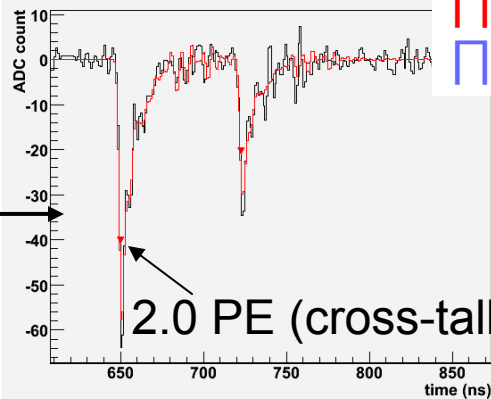
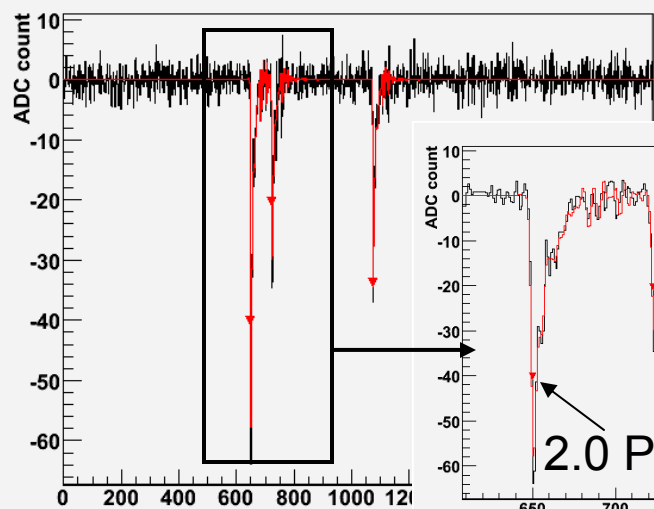
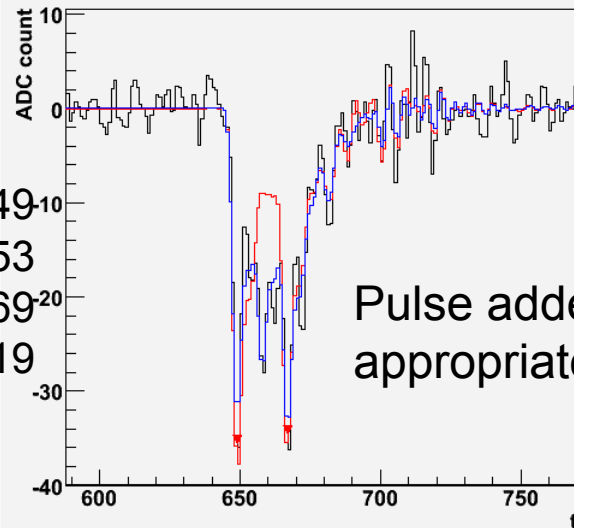
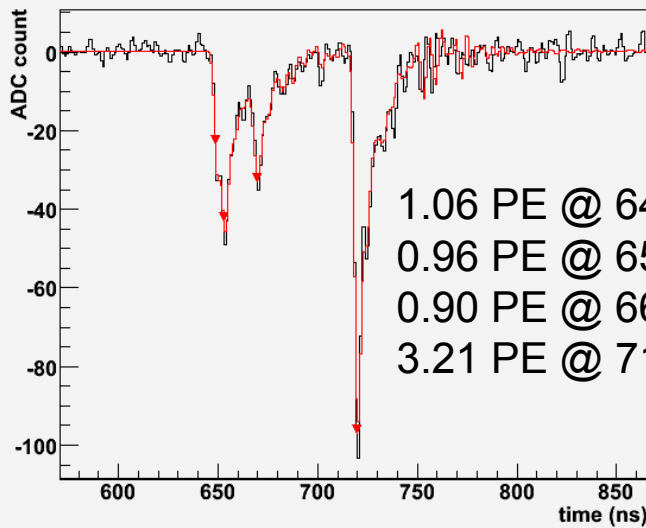
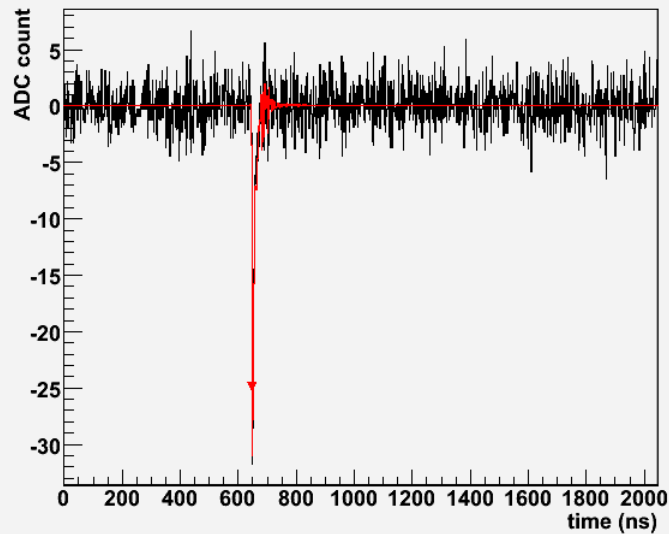
### □ After-pulsing

- Worsen timing resolution when fitting full waveform

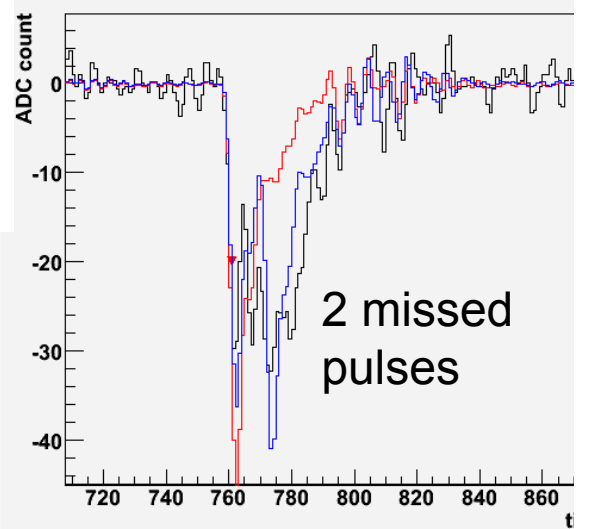
# Measuring Dark noise, cross-talk and after-pulsing

- ❑ Fast recovery biasing scheme: no resistance in series
- ❑ Trigger on Dark noise hits ( $\sim 0.3$  PE threshold)
- ❑ Use fast amplifier (CAEN N978)
- ❑ Use 1 GHz digitizer (CAEN V1789)
- ❑ Search for pulses
  - Extract MPPC\*Amplifier response function
  - Search for pulses based on rise time + fall time + amplitude criteria
  - Fit by a superposition of response functions
    - Add more pulses if poor fit (partial pulse overlap)
  - Pulse finding is the main source of systematic errors

# Typical waveforms with after-pulsing test setup

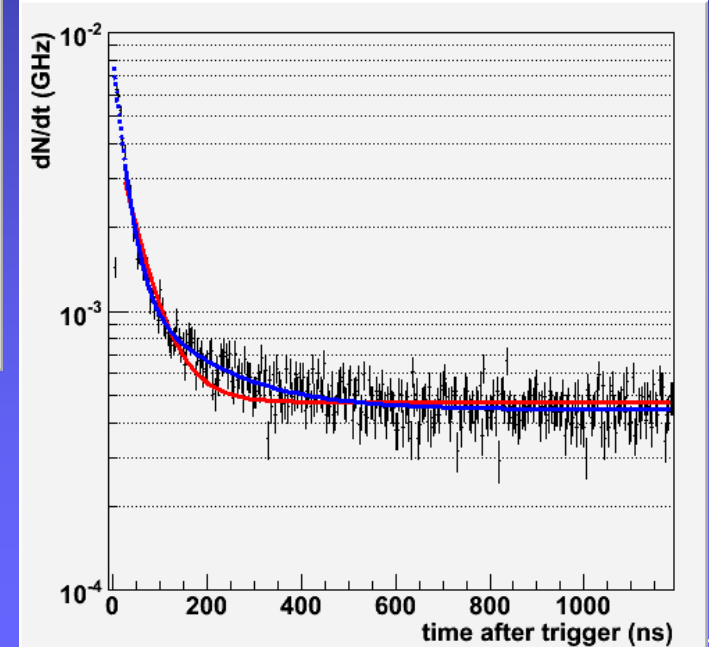
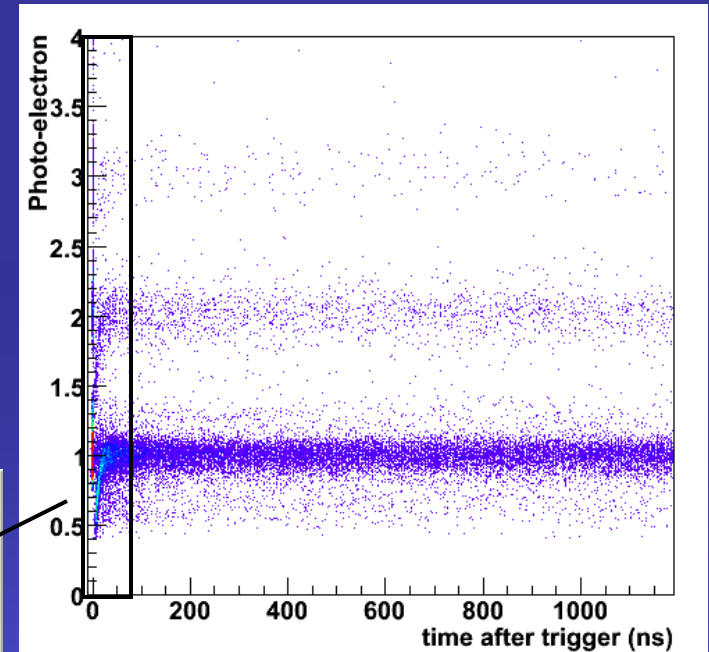
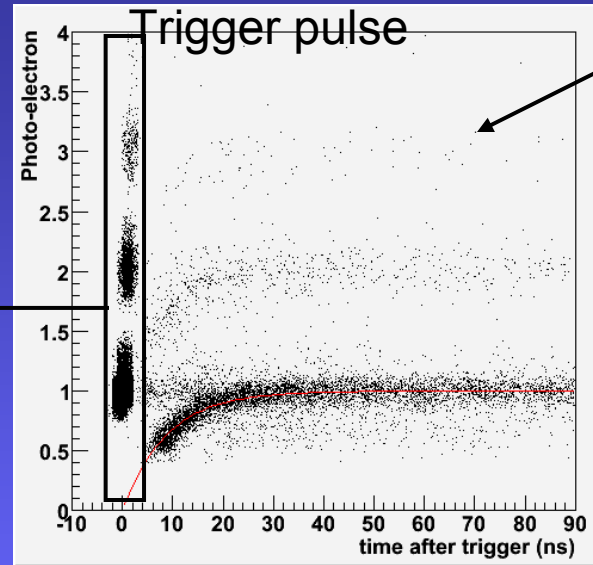
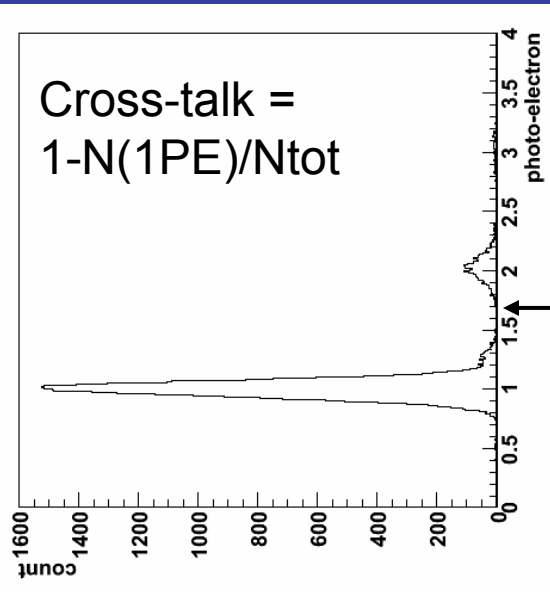


- Data (70V, 25C)
- ▼ pulse finder
- ▭ First pass refit
- ▭ Refit after splitting



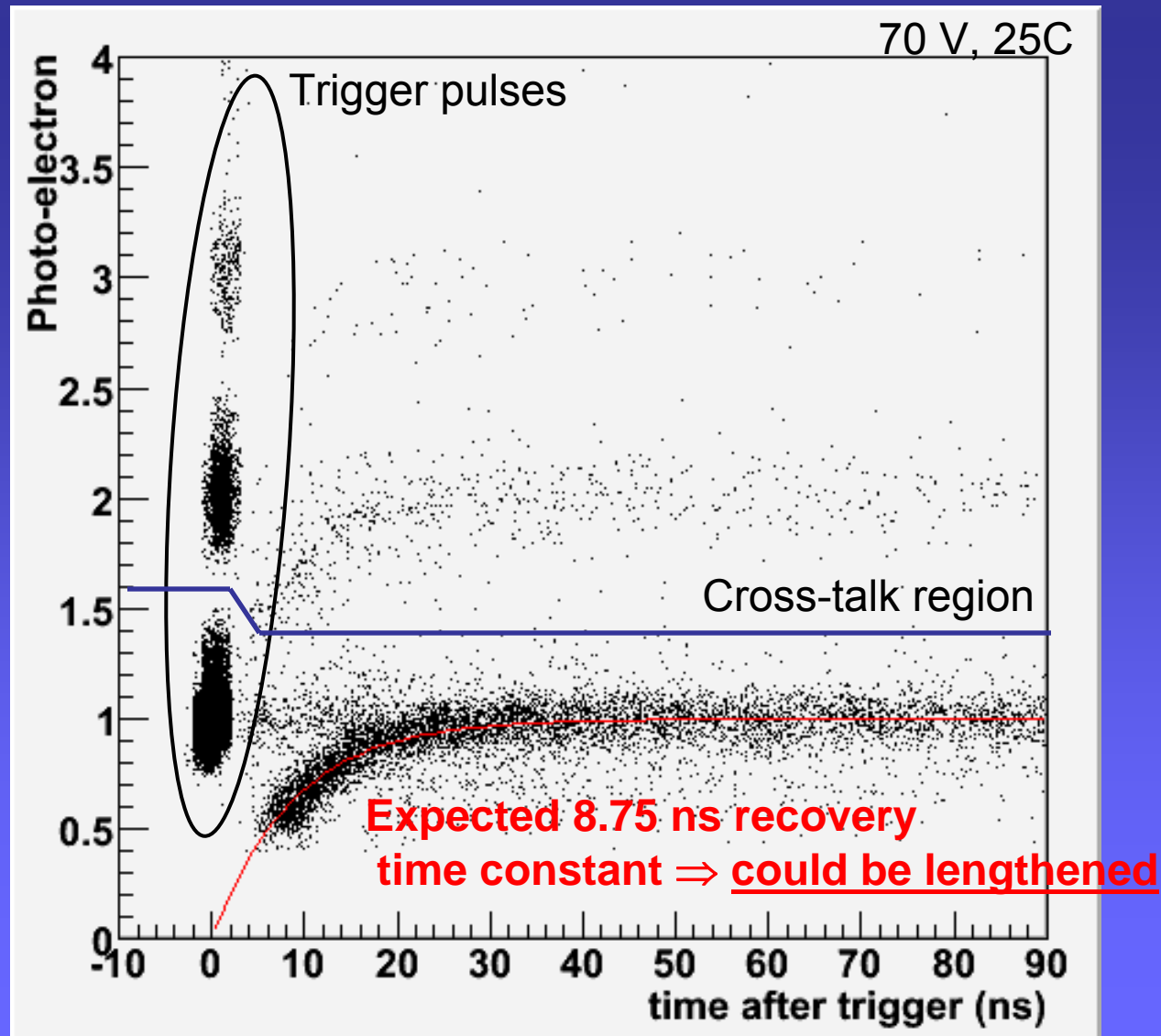
# Amplitude vs time for all pulses

70 V, 25C





# Hit amplitude vs time

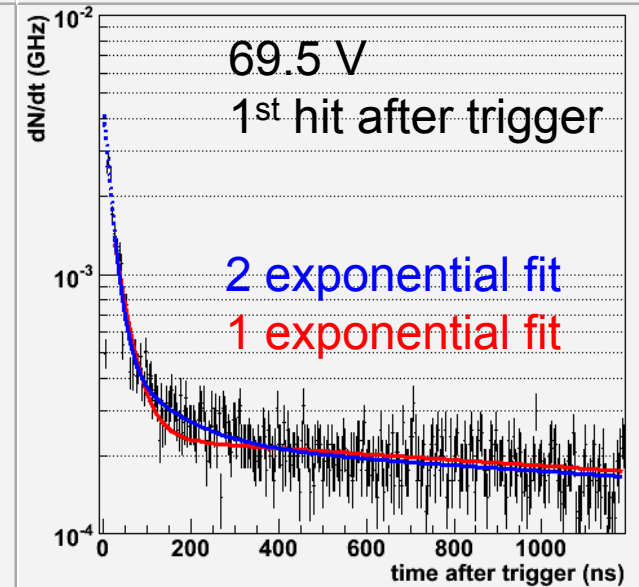
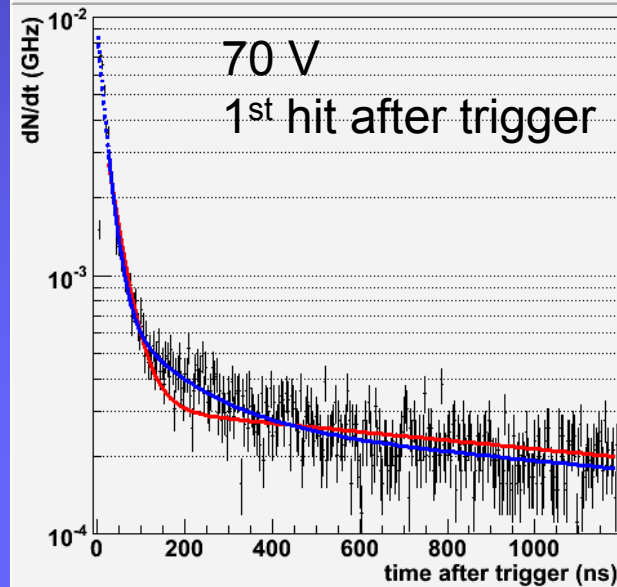
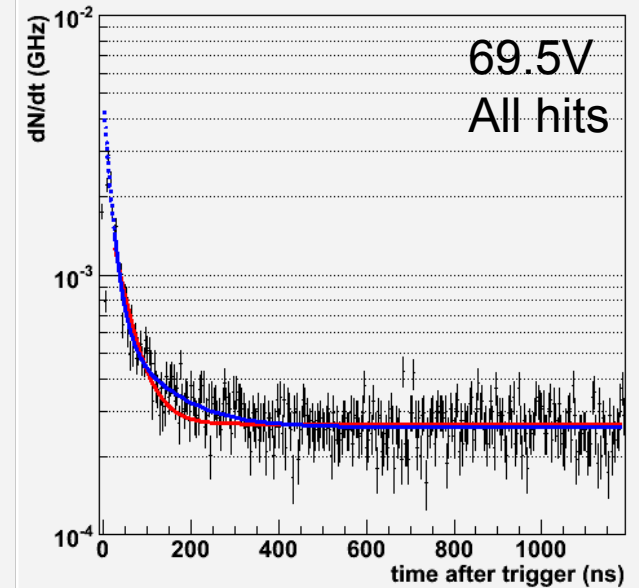
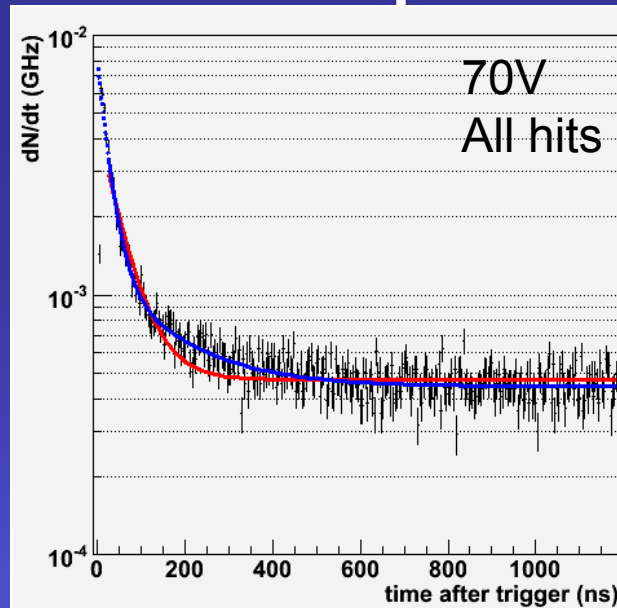


# Reducing after-pulsing by playing with recovery time

- It is possible to reduce after-pulsing by increasing the recovery time
  - Resistance in series with bias
  - Introduce dead time after the pulse
    - Is there an acceptable compromise?
  - For the FGD, readout issue may force us to run with a long recovery time
    - After-pulsing is then automatically reduced
- FGD approach
  - Run a low bias voltage: after-pulsing ~ 10%

# Separating Dark Noise and after-pulsing

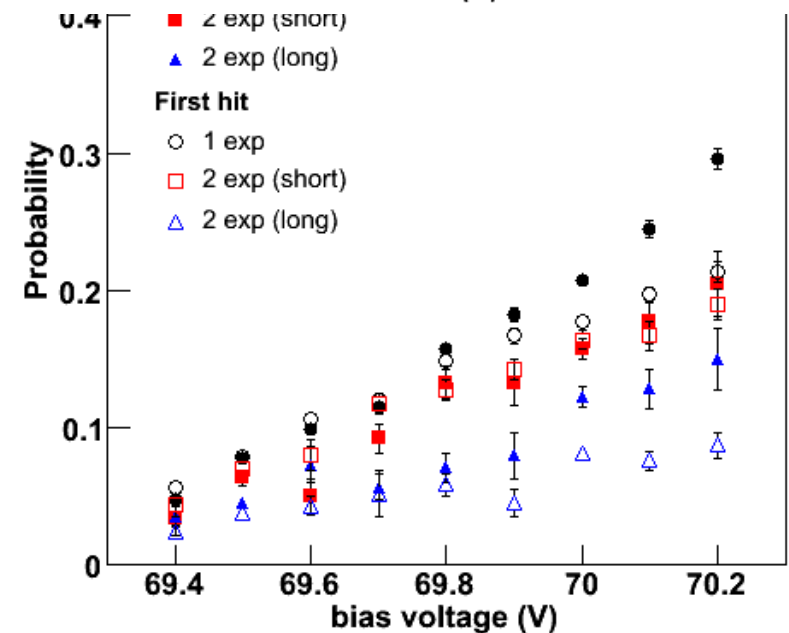
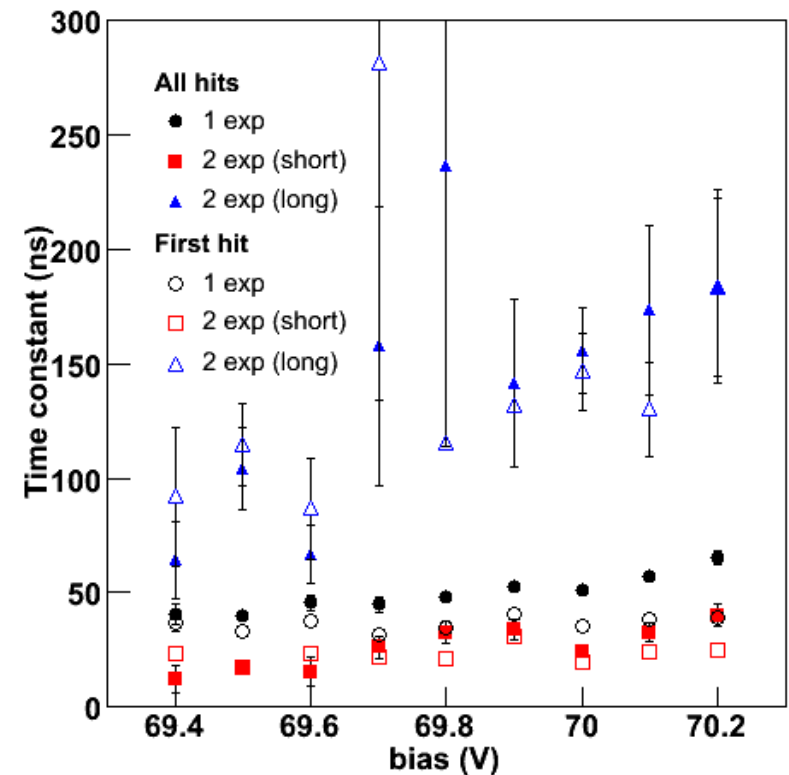
- Count all hits
  - No cross-talk
  - Sensitive to multiple after-pulse
- Histogram the time of the 1<sup>st</sup> hit after trigger
  - No cross-talk
  - No multiples
    - But more complicated fit



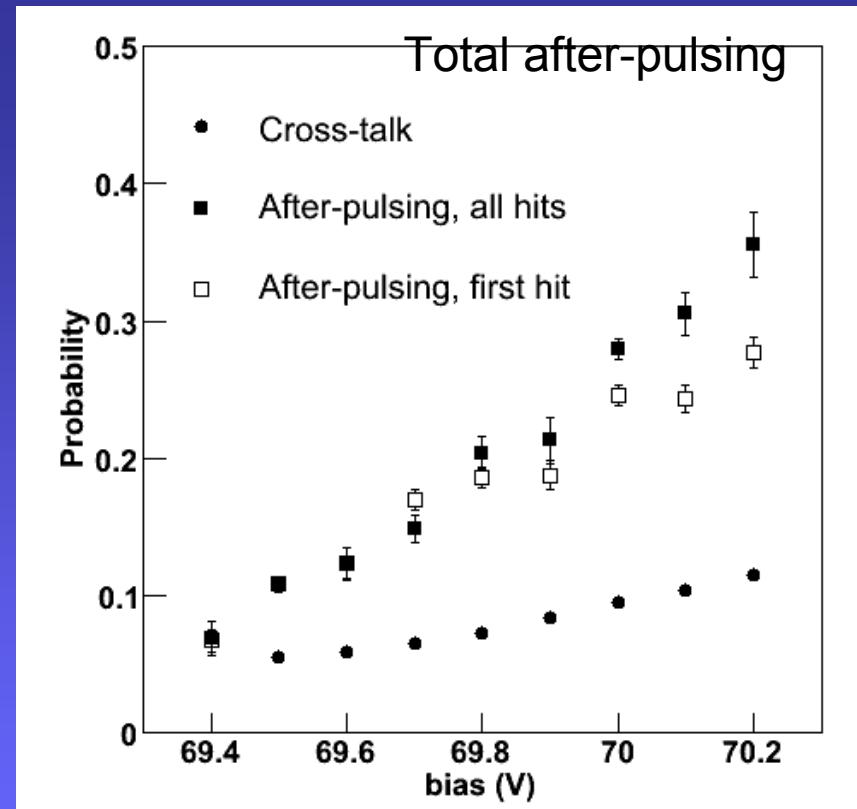
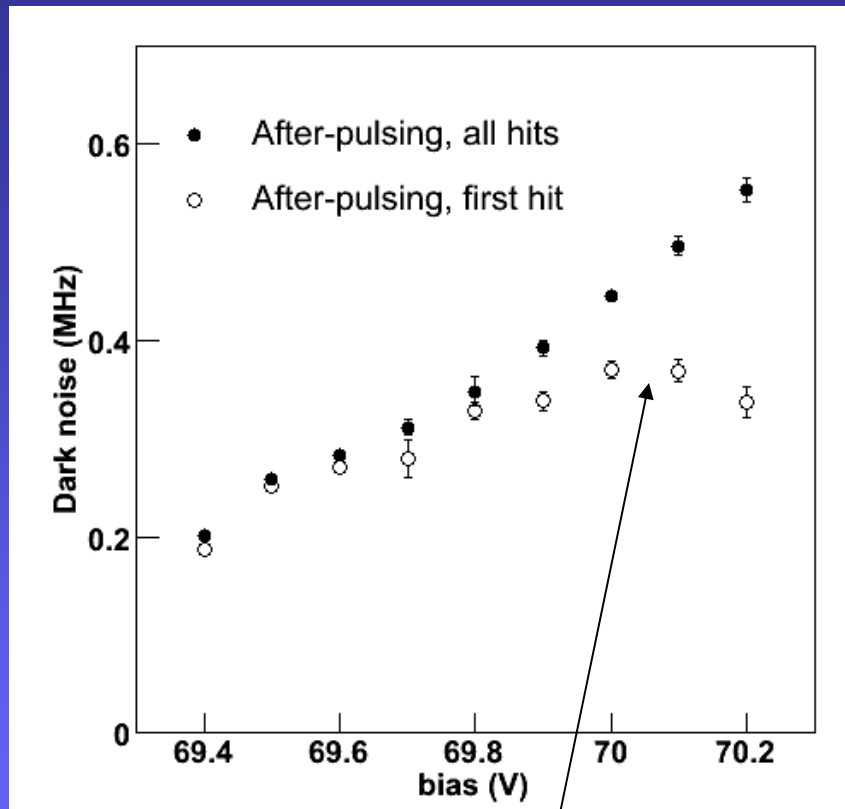
# After-pulsing fit results

□ Fit is impaired by low statistics

- 69.5V and 70V have more statistics
- Long time constant hard to pin down
  - Increase of constant in all hits expected
- Short time constant 20-30 ns
  - Dominate the after-pulsing



# Competing contributions



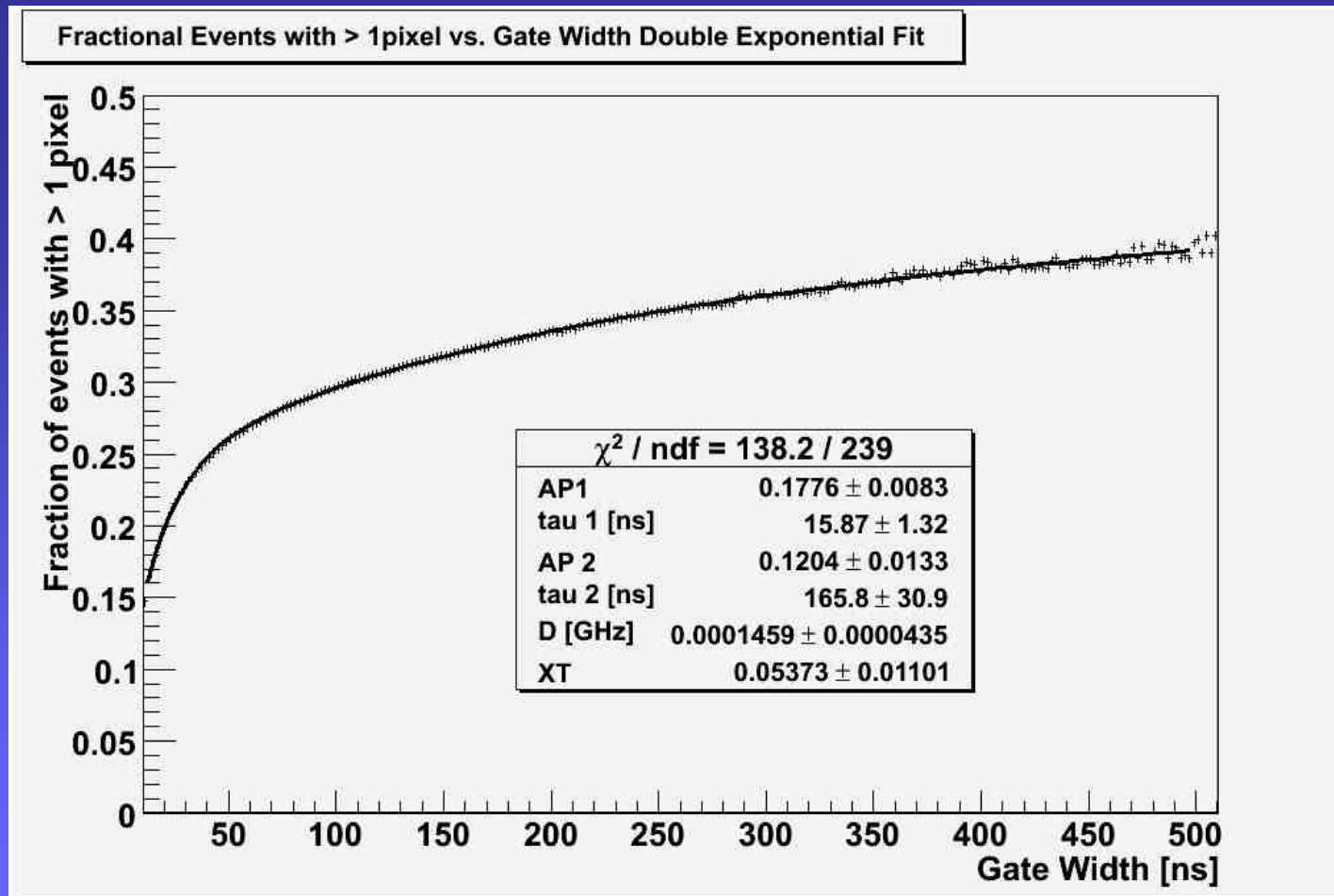
Is dark noise really saturating and the visible increase due to after-pulsing?

# Conclusions

- ❑ MPPC + AFTER combination fulfill FGD requirements
- ❑ MPPC nuisances are under control for the FGD application
  - After-pulsing is dominant
    - Run MPPC at low bias to avoid significant after-pulsing
    - Not a problem. Quantum efficiency is large enough
- ❑ Investigating interplay between recovery, pulse shape, and after-pulsing
  - Is there an optimum design?

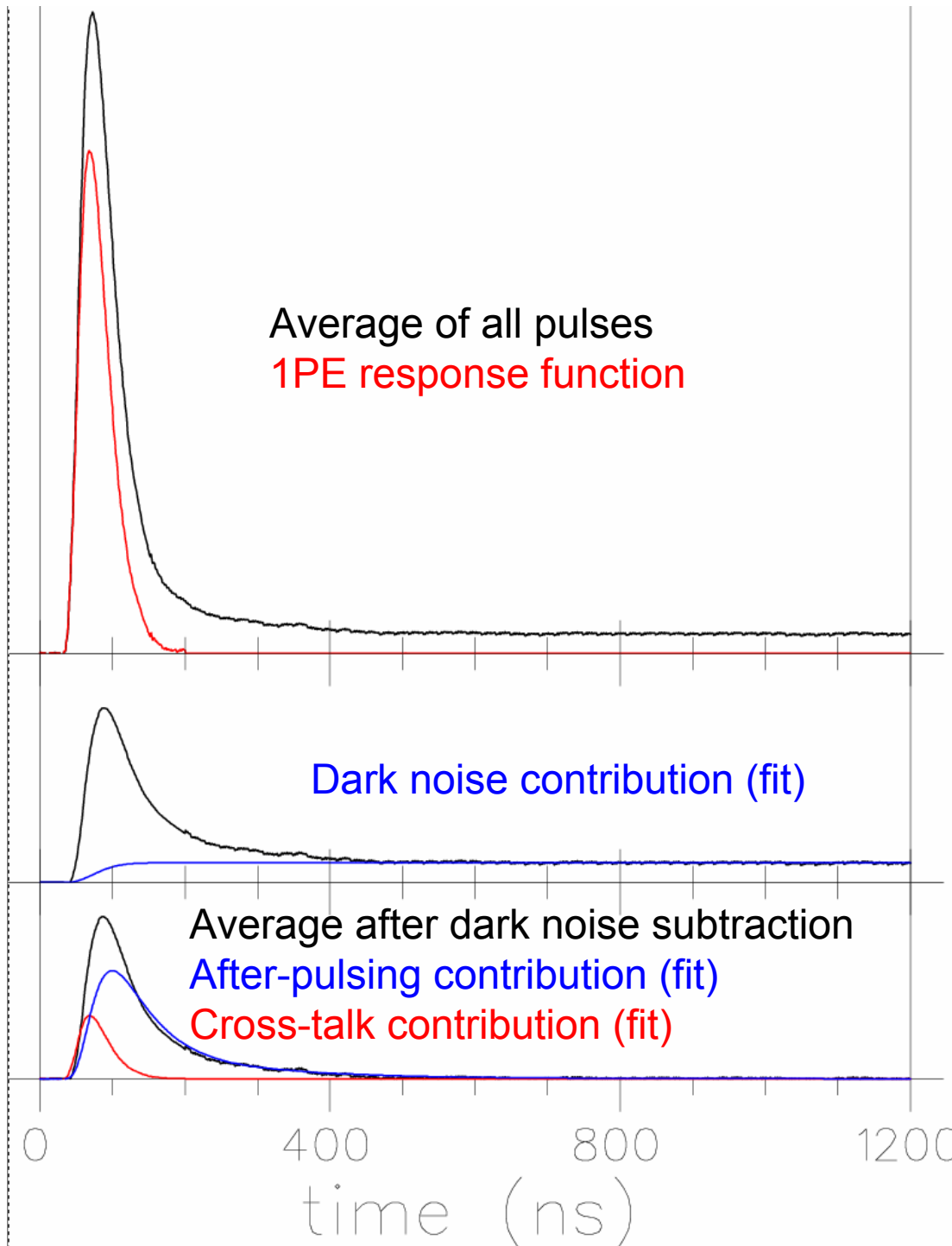
# Back-up

# Measuring after-pulsing with gate technique





# Measuring after-pulsing with average technique



R. Tacik (U. Regina)

# 1<sup>st</sup> hit timing distribution fit function

$$dN / dt = e^{-DN \cdot t} * \left[ (1 - Ap - Ap \cdot e^{\frac{-t}{\tau}}) DN \right] + \frac{Ap}{\tau} e^{\frac{-t}{\tau}} e^{-DN \cdot t}$$

DN = dark noise rate

Ap = After-pulsing probability

$\tau$  = After-pulsing time constant